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August 2014

FQP15P12 / FQPF15P12 P-Channel QFET® MOSFET

-120 V, -15 A, 0.2 Ω

Description

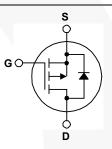
This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor[®]'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- -15 A, -120 V, $R_{DS(on)}$ = 0.2 Ω (Max.) @ V_{GS} =-10 V, I_D = -7.5 A
- Low Gate Charge (Typ. 29 nC)
- Low Crss (Typ. 110 pF)
- 100% Avalanche Tested
- · 175°C Maximum Junction Temperature Rating







Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQP15P12	FQPF15P12	Unit
V _{DSS}	Drain-Source Voltage		-120		V
I _D	Drain Current - Continuous (T _C = 25°C	;)	-15	-15 *	Α
	- Continuous (T _C = 100°	C)	-10.6	-10.6 *	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	-60	-60 *	Α
V_{GSS}	Gate-Source Voltage		± 30		V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	1157		mJ
I _{AR}	Avalanche Current	(Note 1)	-15		Α
E _{AR}	Repetitive Avalanche Energy (Note 1)		10		mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-5.0		V/ns
P _D	Power Dissipation (T _C = 25°C)		100	41	W
	- Derate above 25°C		0.67	0.27	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175		°C
T _L	Maximum Lead Temperature for Soldering 1/8" from Case for 5 Seconds),	3	00	°C

^{*} Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FQP15P12	FQPF15P12	Unit
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	1.5	3.66	°C/W
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.	40		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Symbol	Parameter	Test Conditions		Тур	Max	Unit
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	-120			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μA, Referenced to 25°C		-0.13		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -120 V, V _{GS} = 0 V		-	-1	μΑ
		V _{DS} = -96 V, T _C = 150°C			-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V		-	-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V		ı	100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0		-4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -7.5 A		0.17	0.2	Ω
9 _{FS}	Forward Transconductance	V _{DS} = -40 V, I _D = -7.5 A		9.5		S
Dynamic Characteristics C _{iss} Input Capacitance V _{DS} = -25 V, V _{CS} = 0 V.				850	1100	pF
C _{oss}	Output Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz	\	310	400	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0 WHZ		110	140	pF
	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = -60 V, I _D = -15 A,		15	40	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		100	210	ns
t _{d(off)}	Turn-Off Delay Time	a		80	170	ns
t _f	Turn-Off Fall Time	(Note 4)		80	170	ns
Q_g	Total Gate Charge	$V_{DS} = -96 \text{ V}, I_{D} = -15 \text{ A},$		29	38	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -10 V		5.1		nC
Q_{gd}	Gate-Drain Charge	(Note 4)		15		nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				-15	Α
I _{SM}	faximum Pulsed Drain-Source Diode Forward Current				-60	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -15 A			-4.0	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = -15 A,		126	-	ns
Q _{rr}	Reverse Recovery Charge	dI _E / dt = 100 A/μs		0.61		μC

Notes: 1. Repetitive rating : pulse width limited by maximum junction temperature. 2. L = 6.0mH, I $_{AS}$ = -15A, V $_{DD}$ = -50V, R $_{G}$ = 25 Ω , starting T $_{J}$ = 25°C. 3. I $_{SD}$ ≤ -15A, di/dt ≤ 300A/ μ s, V $_{DD}$ ≤ BV $_{DSS}$, starting T $_{J}$ = 25°C. 4. Essentially independent of operating temperature.

Typical Characteristics

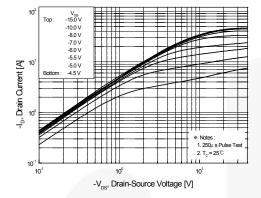


Figure 1. On-Region Characteristics

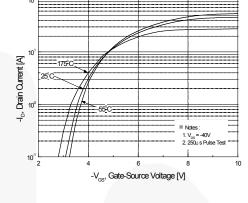


Figure 2. Transfer Characteristics

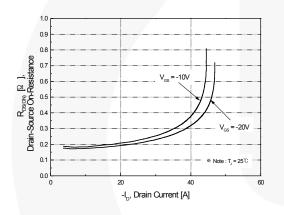


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

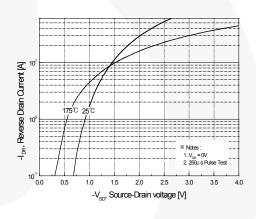


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

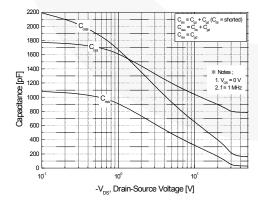


Figure 5. Capacitance Characteristics

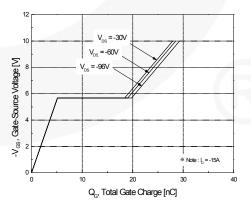


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

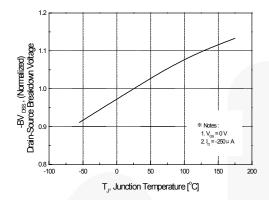


Figure 7. Breakdown Voltage Variation vs Temperature

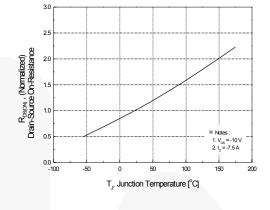


Figure 8. On-Resistance Variation vs Temperature

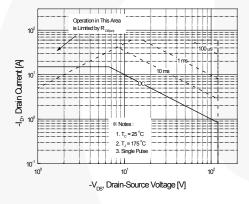


Figure 9-1. Maximum Safe Operating Area for FQP15P12

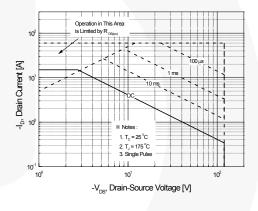


Figure 9-2. Maximum Safe Operating Area for FQPF15P12

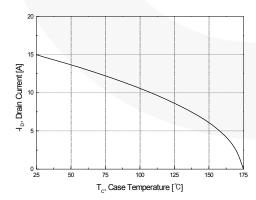


Figure 10. Maximum Drain Current vs Case Temperature

Typical Characteristics (Continued)

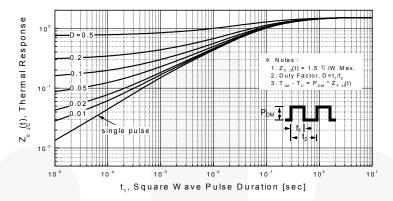


Figure 11-1. Transient Thermal Response Curve for FQP15P12

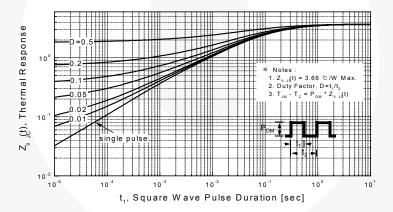


Figure 11-2. Transient Thermal Response Curve for FQPF15P12

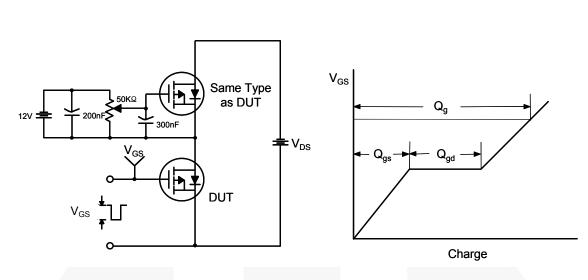


Figure 12. Gate Charge Test Circuit & Waveform

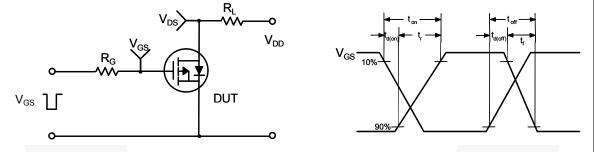


Figure 13. Resistive Switching Test Circuit & Waveforms

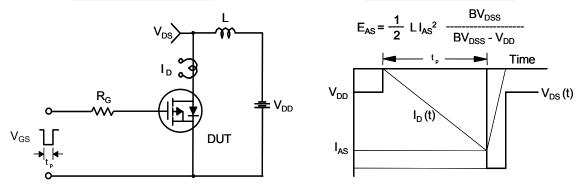
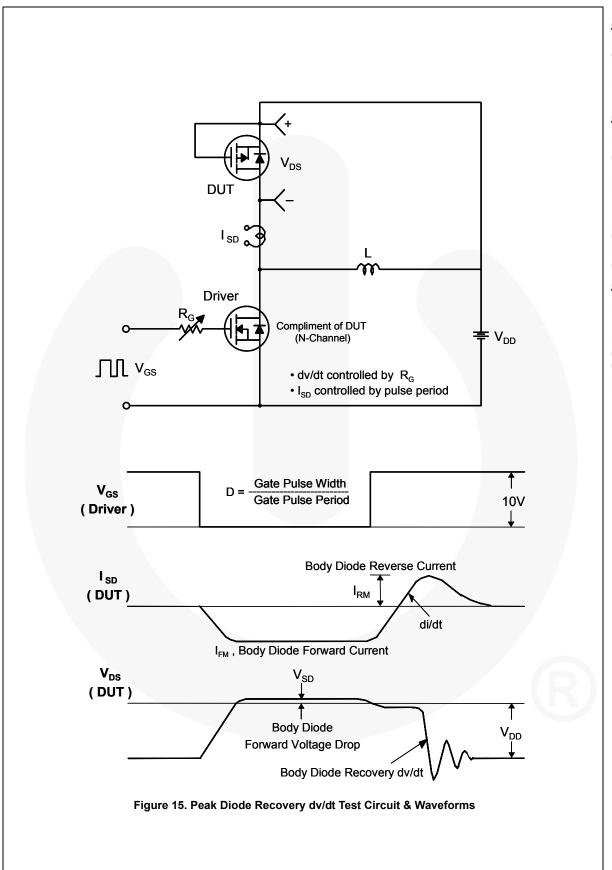
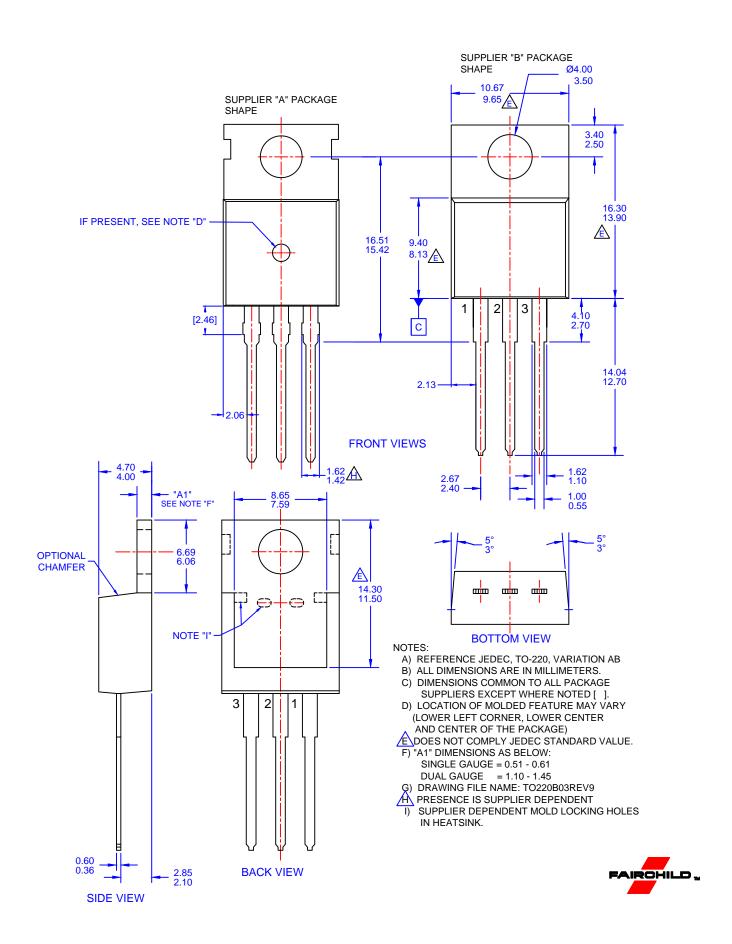
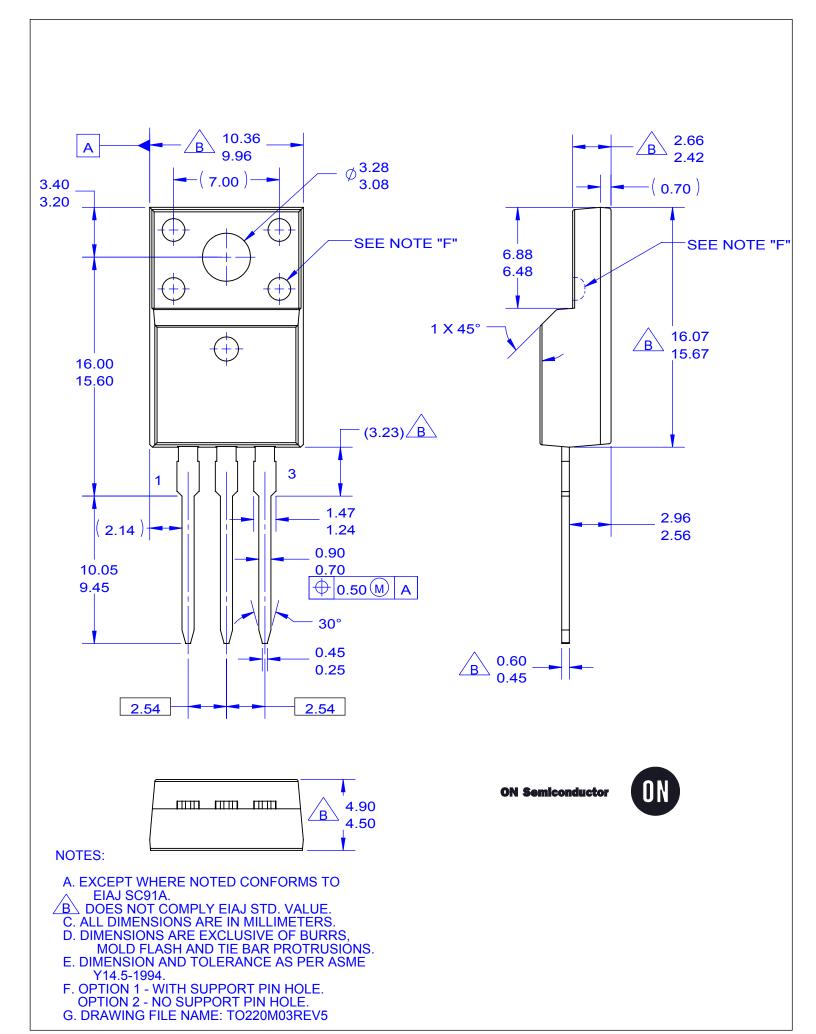


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms







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